Specification MAP/CV57/Is	SECURITY						
Dated 30.4.48 To be read in conjunction K1001, ignoring clauses:- 5.3, 5.8, 7.2.	مسيدي الأرسي	ification TRICTED	Valve UNCLASSIFIED				
	ates a change						
TYPE OF VALVE - Tetrode							
CATHODE - Indirectl	MARKING						
ENVELOPE - Glass-unn	sed	See K1001/4					
RATING		BASE					
	Note	T 4					
Heater Voltage (V)	12.6		See K1001/AIV/D7				
Heater Current (A)	1.75		Pin Electrode				
Max. Anode Voltage (kV) Max. Screen Voltage (kV)	11.0		1 Control grid				
Max. Anode Dissipa-			2 Heater				
tion (W)	15.0		Screen grid Heater & Cathode				
Max. Screen Dissipa- tion (W)	2.5		T.C. Anode				
Max. Grid Bias for cut-			TOP CAP				
off (V)	-800		See K1001/AI/D5.1				
Max. Peak Anode Current (A)	5.0		Dee WicollwallDai				
Max. Peak Screen	7.0		DIMENSIONS				
Current (A)	0.6		See K1001/AI/D1.				
	• •		Dimension Max.				
CAPACITANCES (pF)			Z	(mm)	152	165	
Cae	11.0		B	(mm)		57	
Cge Cag	21.0						
Cag	0.5						
NOTE							
A: - The above ratings app							

as a series modulator with an

off-on ratio of 400 to 1.

CV57

To be performed in addition to those applicable in K1001.

		Tes	t Con	ditions	_			Test	Limits		No.	
	Vh	Vg1	Vg2	Va	Ig2	Ia		. .	Min.	Max.	Tested	Note
8.	Be- tween 12V. and 15V.		- Strapped. Applied voltage raised slowly to 3.5kV. and maintained till flash- ing ceases.			race	SCREEN HOT FLASH PROCESS Applied anode and screen voltage to be maintained at 3.5kV. for a period of one minute without further flashing.				100%	1
þ	ditto	Strapped Raised slowly to 18kV and maintain ed till flashing ceases.				A taxace	ANOTE MOT Frault PROCESS Applied anode voltage to be maintained at 18kV. for a period of one minute without "urther flashing.			100%		
C	12.6	0	0	0	0	0	Ih	(A)	1.55	1.95	100%	
đ	12.6 Maint	ained	200 app	apped. V. lied. 30secs.		+ Ig2 ≡ 5mA.	Ιg	(µA)	-	20	100%	
е	12.6		200	apped. V. lied.	Ia + Ig2 = 75mA.		Vg1	(V)	-30	-4 5	100%	
f	12.6	-	See	Note 2.	.	10µA	Vg1	(V)	3=#	- 25	100%	2
g	5.25 A.C. or D.C.	0	300	apped. V. lied.			Ic	(mA)	15		100%	
h	See	K100	1/AII	I	-		CAPACI 1. Cae 2. Cge	!	6.9 15.75	11.1 26.25	1%(1) 1%(1)	

NOTES

- 1:- Tests (a) and (b) form part of the processing of the valve, and having been met during manufacture they shall not be repeated for acceptance testing. For these hot flash tests, the applied voltage shall be supplied through a circuit as in Fig. 1, page 3.
- 2. For test (f), the anode and screen grid voltages shall be derived from the network as in Fig. 2, page 3.

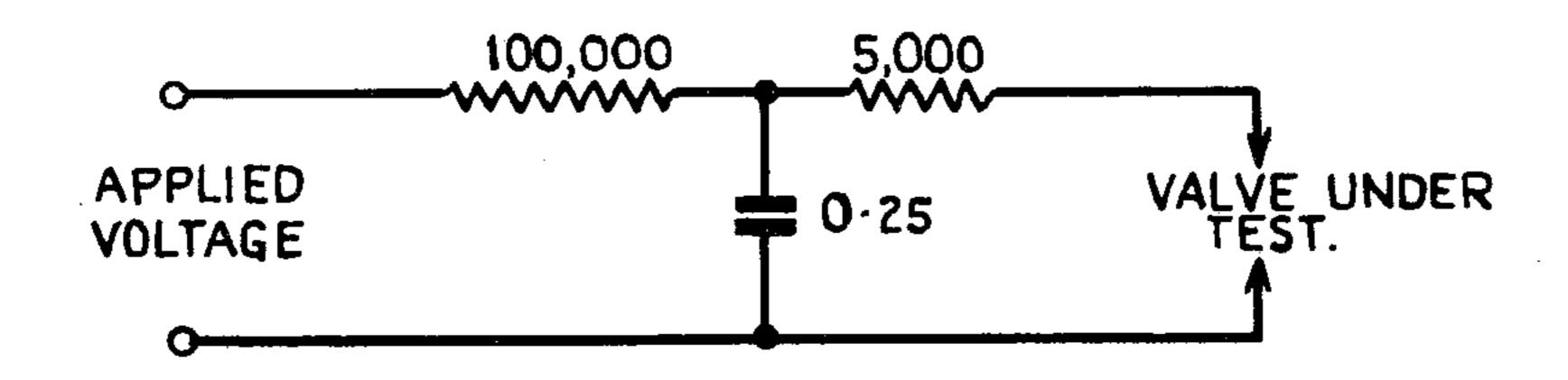


FIG. I.

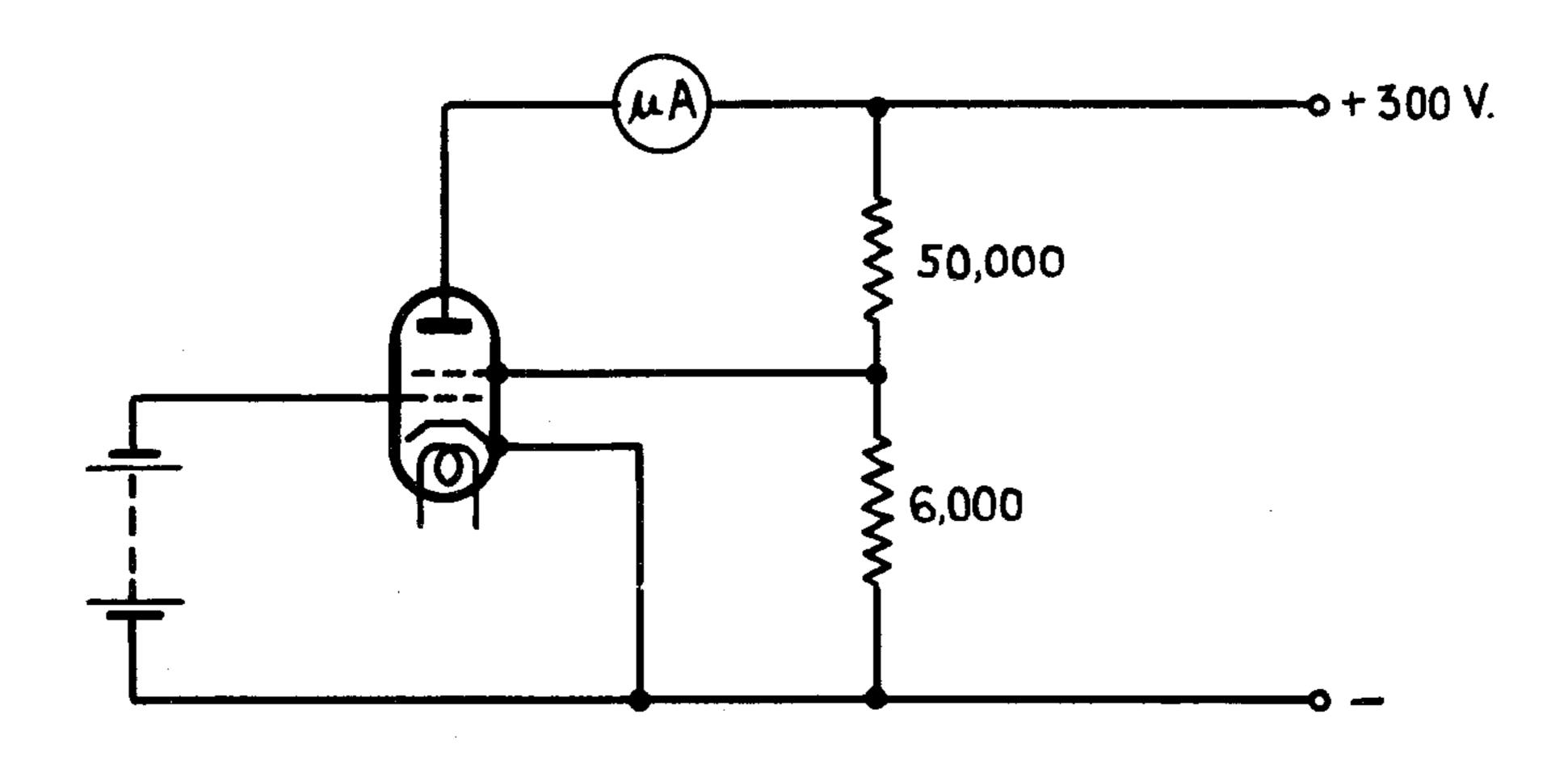


FIG. 2.